

DATA-2016: IEEE INTERNATIONAL WORKSHOP on DEFECTS, ADAPTIVE TEST, YIELD AND DATA ANALYSIS

Will be held in conjunction with ITC 2016, on Nov. 17-18, 2016, In Fort Worth, TX



CALL FOR PAPERS AND PARTICIPATION THEME: "Toward Real Time Understanding"

GENERAL CHAIR

Jennifer Dworak, SMU

PROGRAM CHAIR

Arani Sinha, Intel

VICE-PROGRAM CHAIR

Wesley Smith, Galaxy

FINANCE CHAIR

Sagar Kekare, KLA-Tencor

PUBLICITY & WEB CHAIR

Sankaran Menon, Intel

PUBLICATIONS CHAIR

Chintan Patel, UMBC

PANEL CHAIR

Anne Meixner, The Engineers' Daughter LLC

LOCAL ARRANGEMENTS

David Park, Optimal+

TEST STANDARDS CHAIR

Al Crouch, SiliconAid

EU LIAISON

Rene Segers, Qualtera

STEERING COMMITTEE

Jeffrey Roehr, Texas Instruments
Sankaran Menon, Intel
Adit Singh, Auburn Univ.
M. Tehranipoor, U CT
Hank Walker, Texas A&M
Hans Manhaeve, Q-Star Test
Jim Plusquellic, U. NM

PROGRAM COMMITTEE

Rob Aitken, ARM
Nemat Bidokhti, Cisco
Sreejit Chakravarty, Intel
John Carulli, Global Foundries
Patrick Girard, LIRMM, France
Ajay Khoche, Consultant
Mike Laisne, Qualcomm
Amit Nahar, TI
Suriyaprakash Natarajan, Intel
Jay Orbon, Consultant
John Potter, Asset-Intertech
Rajesh Raina, NXP
Claude Thibeault, ETS, Canada
Li C. Wang, UCSB
Xiaoqing Wen, KIT, Japan
Qiang Xu, CUHK, Hong Kong

The scope of the DATA workshop once again returns to our common theme, which has always been DATA, specifically, semiconductor test and yield data. We in the semiconductor industry create billions of data points every hour, and we've made great strides in capturing, storing, and analyzing these data. As the cost of storage falls, and query and analysis capabilities become ever more powerful, the next horizon for DATA professionals is Real Time Understanding. How quickly can we turn our copious data from wafer sort, final test, in-line defect inspection, etc. into an understanding that leads to immediate or even pre-emptive action? The time and cost pressures we're facing as an industry make the move towards short-loop process improvement an imperative.

The Organizing Committee for the DATA-2016 Workshop is soliciting papers in the area of semiconductor test, yield analysis, learning, and improvement. Of particular interest are advanced techniques and new tools for approaching Real Time Understanding of yield loss drivers, tester & manufacturing efficiency, & outlier detection in semiconductor manufacturing, including implementation of adaptive test. Preference will be given to real-world case studies.

Ideas or proposals for Embedded Tutorials, Debates, Panel Discussions and **Poster style "Spot-Light"** presentations describing industrial experiences or research are also invited.

Suggested Topics

Real Time Analysis Methods
Real Time Test Process Monitoring
Yield Learning and Analysis
Analog Fault modeling and coverage
Analog effects in Digital Logic
Embedded Instrumentation (iJTAG)
Advanced dppm reduction & reliability improvement techniques

Data Acquisition & Transport
Adaptive Test for Product Engineers
Data Analysis methods, including multivariate data
Fault Localization and Diagnosis
Data storage and security
I/O Test, Tuning, and Adjustment
Product and Project Case studies

To present at the workshop, send to arani.sinha@intel.com a PDF version of an extended abstract or a full paper (Max 10 pages, double column, 11pt font size, [IEEE proceeding format](#)) by **October 7, 2016**. Each submission should include full name and address of each author, affiliation, telephone number, FAX and Email address. Camera-ready papers for inclusion in the digest of papers will be due on **November 4, 2016**.

AUTHOR'S SCHEDULE

Submission Date:
Notification of Acceptance:
Camera Ready Paper (.pdf):
Final Presentation Slides (.ppt):

Web-site at: <http://DATA.ttc-events.org/>

October 7, 2016 (extended)
October 21, 2016
November 4, 2016
November 9, 2016

General Information:

Jennifer Dworak
Southern Methodist University, USA.
E-mail: jdworak@lyle.smu.edu

Technical Program Submissions:

Arani Sinha
Intel, USA.
E-mail: Arani.Sinha@INTEL.com

DATA-2016 is sponsored by:

